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Bulletin Date: 6/24/2016		Bulletin Effective Date: 6/24/2016			
Title: EFR32MG1, EFR32BG1 & EFR32FG1 Revision C0					
Bulletin Details					
Description: Silicon Labs is pleased to announce hardware revision C of the EFR32MG1 Mighty Gecko ZigBee® & Thread, EFR32BG1 Blue Gecko Bluetooth® Smart and EFR32FG1 Flex Gecko Proprietary Wireless SoC families. After the effective date of this PCN, Silicon Labs plans to deliver Revision C for customers ordering Revision B. Datasheets and errata have been updated for these products. The new revision is a pin-compatible replacement for the previous revision devices. Please see attached Qualification Report in the Appendix. The datasheet are updated to version 0.951. The Rev C errata documents and updated Errata History documents are also available. Revision C eliminated the following errata in revision B:					
Errata #	Designator	Title/Problem	Workaround Exists	Affected Revision	Fixed Revision
1	CUR_E202	EM2/3 Current Consumption at Cold Temperatures	No	B	B, date code 1547 (November 16, 2015)
2	GPIO_E201	GPIO Default Slew Rate	Yes	B	B, date code 1603 (January 18, 2015)
3	DCDC_E201	DCDC Stops Regulating During a Fast EM0/1 to EM2/3/4H Transition	Yes	B	C
Reason: Revision C is the full production (FP) version of all OPNs in the EFR32MG1, EFR32BG1 and EFR32FG1 families.					
Product Identification:					
Affected Revision B0 OPN			New Revision C0 OPN		
EFR32MG1P232F256GM48-B0			EFR32MG1P232F256GM48-C0		
EFR32MG1P232F256GM48-B0R			EFR32MG1P232F256GM48-C0R		
EFR32MG1P232F256GM32-B0			EFR32MG1P232F256GM32-C0		
EFR32MG1P232F256GM32-B0R			EFR32MG1P232F256GM32-C0R		
EFR32MG1P132F256GM48-B0			EFR32MG1P132F256GM48-C0		
EFR32MG1P132F256GM48-B0R			EFR32MG1P132F256GM48-C0R		
EFR32MG1P132F256GM32-B0			EFR32MG1P132F256GM32-C0		
EFR32MG1P132F256GM32-B0R			EFR32MG1P132F256GM32-C0R		
EFR32MG1B232F256GM48-B0			EFR32MG1B232F256GM48-C0		
EFR32MG1B232F256GM48-B0R			EFR32MG1B232F256GM48-C0R		
EFR32MG1B232F256GM32-B0			EFR32MG1B232F256GM32-C0		
EFR32MG1B232F256GM32-B0R			EFR32MG1B232F256GM32-C0R		



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EFR32MG1B132F256GM48-B0	EFR32MG1B132F256GM48-C0
EFR32MG1B132F256GM48-B0R	EFR32MG1B132F256GM48-C0R
EFR32MG1B132F256GM32-B0	EFR32MG1B132F256GM32-C0
EFR32MG1B132F256GM32-B0R	EFR32MG1B132F256GM32-C0R
EFR32MG1V132F256GM48-B0	EFR32MG1V132F256GM48-C0
EFR32MG1V132F256GM48-B0R	EFR32MG1V132F256GM48-C0R
EFR32MG1V132F256GM32-B0	EFR32MG1V132F256GM32-C0
EFR32MG1V132F256GM32-B0R	EFR32MG1V132F256GM32-C0R
EFR32BG1P332F256GM48-B0	EFR32BG1P332F256GM48-C0
EFR32BG1P332F256GM48-B0R	EFR32BG1P332F256GM48-C0R
EFR32BG1P332F256GM32-B0	EFR32BG1P332F256GM32-C0
EFR32BG1P332F256GM32-B0R	EFR32BG1P332F256GM32-C0R
EFR32BG1P232F256GM48-B0	EFR32BG1P232F256GM48-C0
EFR32BG1P232F256GM48-B0R	EFR32BG1P232F256GM48-C0R
EFR32BG1P232F256GM32-B0	EFR32BG1P232F256GM32-C0
EFR32BG1P232F256GM32-B0R	EFR32BG1P232F256GM32-C0R
EFR32BG1B232F256GM48-B0	EFR32BG1B232F256GM48-C0
EFR32BG1B232F256GM48-B0R	EFR32BG1B232F256GM48-C0R
EFR32BG1B232F256GM32-B0	EFR32BG1B232F256GM32-C0
EFR32BG1B232F256GM32-B0R	EFR32BG1B232F256GM32-C0R
EFR32BG1B232F128GM48-B0	EFR32BG1B232F128GM48-C0
EFR32BG1B232F128GM48-B0R	EFR32BG1B232F128GM48-C0R
EFR32BG1B232F128GM32-B0	EFR32BG1B232F128GM32-C0
EFR32BG1B232F128GM32-B0R	EFR32BG1B232F128GM32-C0R
EFR32BG1B132F256GM48-B0	EFR32BG1B132F256GM48-C0
EFR32BG1B132F256GM48-B0R	EFR32BG1B132F256GM48-C0R
EFR32BG1B132F256GM32-B0	EFR32BG1B132F256GM32-C0
EFR32BG1B132F256GM32-B0R	EFR32BG1B132F256GM32-C0R
EFR32BG1B132F128GM48-B0	EFR32BG1B132F128GM48-C0
EFR32BG1B132F128GM48-B0R	EFR32BG1B132F128GM48-C0R
EFR32BG1B132F128GM32-B0	EFR32BG1B132F128GM32-C0
EFR32BG1B132F128GM32-B0R	EFR32BG1B132F128GM32-C0R
EFR32BG1V132F256GM48-B0	EFR32BG1V132F256GM48-C0
EFR32BG1V132F256GM48-B0R	EFR32BG1V132F256GM48-C0R
EFR32BG1V132F256GM32-B0	EFR32BG1V132F256GM32-C0
EFR32BG1V132F256GM32-B0R	EFR32BG1V132F256GM32-C0R
EFR32BG1V132F128GM48-B0	EFR32BG1V132F128GM48-C0
EFR32BG1V132F128GM48-B0R	EFR32BG1V132F128GM48-C0R
EFR32BG1V132F128GM32-B0	EFR32BG1V132F128GM32-C0
EFR32BG1V132F128GM32-B0R	EFR32BG1V132F128GM32-C0R
EFR32FG1P132F256GM48-B0	EFR32FG1P132F256GM48-C0
EFR32FG1P132F256GM48-B0R	EFR32FG1P132F256GM48-C0R
EFR32FG1P132F256GM32-B0	EFR32FG1P132F256GM32-C0
EFR32FG1P132F256GM32-B0R	EFR32FG1P132F256GM32-C0R
EFR32FG1V132F256GM48-B0	EFR32FG1V132F256GM48-C0
EFR32FG1V132F256GM48-B0R	EFR32FG1V132F256GM48-C0R
EFR32FG1P132F128GM48-B0	EFR32FG1P132F128GM48-C0
EFR32FG1P132F128GM48-B0R	EFR32FG1P132F128GM48-C0R
EFR32FG1V132F256GM32-B0	EFR32FG1V132F256GM32-C0
EFR32FG1V132F256GM32-B0R	EFR32FG1V132F256GM32-C0R
EFR32FG1P132F128GM32-B0	EFR32FG1P132F128GM32-C0
EFR32FG1P132F128GM32-B0R	EFR32FG1P132F128GM32-C0R



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EFR32FG1P132F64GM48-B0	EFR32FG1P132F64GM48-C0
EFR32FG1P132F64GM48-B0R	EFR32FG1P132F64GM48-C0R
EFR32FG1V132F128GM48-B0	EFR32FG1V132F128GM48-C0
EFR32FG1V132F128GM48-B0R	EFR32FG1V132F128GM48-C0R
EFR32FG1P132F64GM32-B0	EFR32FG1P132F64GM32-C0
EFR32FG1P132F64GM32-B0R	EFR32FG1P132F64GM32-C0R
EFR32FG1V132F128GM32-B0	EFR32FG1V132F128GM32-C0
EFR32FG1V132F128GM32-B0R	EFR32FG1V132F128GM32-C0R
EFR32FG1V132F64GM48-B0	EFR32FG1V132F64GM48-C0
EFR32FG1V132F64GM48-B0R	EFR32FG1V132F64GM48-C0R
EFR32FG1V132F32GM48-B0	EFR32FG1V132F32GM48-C0
EFR32FG1V132F32GM48-B0R	EFR32FG1V132F32GM48-C0R
EFR32FG1V132F64GM32-B0	EFR32FG1V132F64GM32-C0
EFR32FG1V132F64GM32-B0R	EFR32FG1V132F64GM32-C0R
EFR32FG1V132F32GM32-B0	EFR32FG1V132F32GM32-C0
EFR32FG1V132F32GM32-B0R	EFR32FG1V132F32GM32-C0R

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Customer Actions Needed:
Please qualify and use Rev C0 for any future needs. Revision B0 OPNs listed above are engineering samples and should not be used for Production.

Appendix
EFR32xG1-GM Rev C0 Qualification Report


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Part Rev C0, TSMC Fabrication, SPIL Assembly							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A – Accelerated Environment Stress Tests - 7x7 QFN							
HAST	JA110	3 lots, N=>25	Q038584	0/43	1	3 lots 0/96	Pass
	130°C, 85%RH		Q038040	0/28	1		
	Vcc=3.8V, 96 hours		Q037588	0/25	1		
UHAST	JA110	3 lots, N=>25	Q038123	0/28	1	3 lots 0/83	Pass
	130°C, 85%RH		Q038039	0/28	1		
	Vcc=3.8V, 96 hours		Q037724	0/27	1		
Temp Cycle	JA104	3 lots, N=>25	Q037586	0/25	1	3 lots 0/80	Pass
	Cond C: -65°C to 150°C		Q038041	0/28	1		
	500 cycles		Q038121	0/27	1		
HTSL	JA103	3 lots, N=>25	Q038038	0/28	1	3 lots 0/81	Pass
	150°C, 1000hr		Q038124	0/28	1		
			Q037590	0/25	1		
Test Group A – Accelerated Environment Stress Tests - 5x5 QFN							
HAST	JA110	3 lots, N=>25	Q038584	0/43	1	3 lots 0/96	Pass
	130°C, 85%RH		Q038040	0/28	1		
	Vcc=3.8V, 96 hours		Q037588	0/25	1		
UHAST	JA110	3 lots, N=>25	Q038014	0/35	1	3 lots 0/97	Pass
	130°C, 85%RH		Q038013	0/35	1		
	Vcc=3.8V, 96 hours		Q037772	0/27	1		
Temp Cycle	JA104	3 lots, N=>25	Q037776	0/27	1	3 lots 0/97	Pass
	Cond C: -65°C to 150°C		Q038010	0/35	1		
	500 cycles		Q038009	0/35	1		
HTSL	JA103	3 lots, N=>25	Q038012	0/35	1	3 lots 0/97	Pass
	150°C, 1000hr		Q038011	0/35	1		
			Q037774	0/27	1		
Test Group B – Accelerated Lifetime Simulation Tests							
HTOL	JA108	3 lots, N=>77	Q038136	0/80		4 lots 0/290	Pass
	T _J ≥ 125°C, Dynamic		Q038102	0/53			
	Vcc=3.8V, 1000 hours		Q037998	0/78			
			Q037622	0/79			
LTOL	JA108	1 lot, N=>32	Q037624	0/40		1 lots 0/40	Pass
	T _A = -10°C, Dynamic						
ELFR	Vcc=3.8V, 1000 hours	3 lots, N=>500				4 lots 0/2021	Pass
	JA108		Q038755	0/501			
	T _J ≥ 125°C, Dynamic		Q037570	0/508			
	Vcc=3.8V, 48 hours		Q037999	0/507			
			Q038137	0/505			

Approved by: K. Torres

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Prepared on: 21 June 2016

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Part Rev C0, TSMC Fabrication, SPIL Assembly							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
NVM Endurance, Retention and Operating Life	JESD22-A117 25°C 500 hours	3 lots, N=>39	Q038148	0/40	2		
			Q038147	0/40	2	3 lots	
			Q037725	0/40	2	0/120	Pass
NVM Endurance, Retention and Operating Life	JESD22-A117 125°C 1000 hours	3 lots, N=>39	Q038066	0/40	3		
			Q038028	0/40	3		
			Q038024	1/39	3, 4	4 lots	
			Q037652	0/40	3	1/159	Pass
Test Group E – Electrical Verification							
ESD-HBM	JA114	1 lot, N=>3	Q038744 Q038770				Class 2 Class 2
ESD-CDM	JC101	1 lot, N=>3	Q038750 Q038849		5 6		Class C2 Class C2
Latch Up	JESD78 ±100mA	1 lot, N=>3	Q038754 Q038741	25 °C 25 °C			Pass
Latch Up	JESD78 ±100mA	1 lot, N=>3	Q038753 Q038742	125 °C 125 °C			Pass

Notes:

- Parts are Pre-conditioned at MSL2/260°C
- Preconditioned with 10K write/erase cycles at 25°C
- Preconditioned with 10K write/erase cycles at 125°C
- Failure analysis on the failure was inconclusive. An additional 40 units were stressed from the same wafer lot (Q038028) to reduce the LTPD% below the requirement. LTPD% = 5.76 at 90% confidence with 0 fails and a sample size = 40. LTPD% = 4.80 at 90% confidence with 1 failure and a sample size = 80.
- Results for 7x7 QFN package, 2.4 GHz bond out
- Results for 5x5 QFN package, 2.4 GHz

EFR32xG1-GM Rev C0 Qualification Report



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Part Rev C0, TSMC Fabrication, SPIL Assembly

Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
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This report applies to the following part numbers:

EFR32MG1P232F256GM48-C0	EFR32BG1B132F128GM48-C0
EFR32MG1P232F256GM32-C0	EFR32BG1B132F128GM32-C0
EFR32MG1P132F256GM48-C0	EFR32BG1V132F256GM48-C0
EFR32MG1P132F256GM32-C0	EFR32BG1V132F256GM32-C0
EFR32MG1B232F256GM48-C0	EFR32BG1V132F128GM48-C0
EFR32MG1B232F256GM32-C0	EFR32BG1V132F128GM32-C0
EFR32MG1B132F256GM48-C0	EFR32FG1P132F256GM48-C0
EFR32MG1B132F256GM32-C0	EFR32FG1P132F256GM32-C0
EFR32MG1V132F256GM48-C0	EFR32FG1V132F256GM48-C0
EFR32MG1V132F256GM32-C0	EFR32FG1P132F128GM48-C0
EFR32BG1P332F256GM48-C0	EFR32FG1V132F256GM32-C0
EFR32BG1P332F256GM32-C0	EFR32FG1P132F128GM32-C0
EFR32BG1P232F256GM48-C0	EFR32FG1P132F64GM48-C0
EFR32BG1P232F256GM32-C0	EFR32FG1V132F128GM48-C0
EFR32BG1B232F256GM48-C0	EFR32FG1P132F64GM32-C0
EFR32BG1B232F256GM32-C0	EFR32FG1V132F128GM32-C0
EFR32BG1B232F128GM48-C0	EFR32FG1V132F64GM48-C0
EFR32BG1B232F128GM32-C0	EFR32FG1V132F32GM48-C0
EFR32BG1B132F256GM48-C0	EFR32FG1V132F64GM32-C0
EFR32BG1B132F256GM32-C0	EFR32FG1V132F32GM32-C0